SiW ECAL 2017 Beam Test: raw2root + data quality checks

Data Integrity:

- Data structure
- Data integrity information
- Tagging "bad" events:
 - Badbcid definition
 - Improvements?

LAL

A. Irles, Orsay 7th July 2017









The root macro checks the data bytes and headers.

- If additional word is found: warning message and shift of the counter
- If no additional word is found but spill candidate packet has wrong length (in words) → error message and reject spill candidate (count)
- Else: if bad number of columns → error message and reject spill candidate (count)
- Else: if bad chip id → error message and reject spill candidate (count)
- Else: if error in bits → error message and reject spill candidate (count)

In this case, we also save (if possible) the bcid andsca were the error happened







Data Integrity histogram (spill based):

- value = 0 --> OK
- value = 1 --> bad data size
- value = 2 --> more than 15 memory columns
- value = 3 --> bad chip number
- value = 4 --> extra bits in BCID (>12)
- value = 5 --> extra bits in LOW GAIN charge/hbits --> expected 13 bits, no more. The 14th is for autogain mode --> not used
- value = 6 --> extra bits in HIGH GAIN charge/hbits --> expected 13 bits, no more. The 14th is for autogain mode --> not used
- value = 7 --> hit bit from high gain != hit bit from low gain
- value = 8 --> Bad number of columns or bad number of channels
- Error tagging is not cumulative: if bcid is wrong but hit bit s also wrong, the event is tagged as hit bit wrong.

Saved in the .raw.root file



Example for layer 1 (slab 21): Full mip scan



A MARIE CURIE FELLOWSHIP PROGRAM





Example for layer 1 (slab 21): Full mip scan



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Why there are no errors in chips 0,1,2?

Are these chips superseeded by other sources that are not chip-taggable (i.e. bad number of columns, bad chip id, bad number of words)

BCID+1 events

This are not bad events !!

■ Next SCA (NSCA+1) is filled with a zero, but SCA=NSCA is usable \rightarrow not remove from analysis !

 $\blacksquare \sim 15\%$ of chances of happening (reduced to ~ 0 in skiroc2a)

Retriggers, plane events and underflow data

Retrigger: different issue than BCID+1 but similar "signature"

- Retrigger creates lots of entries in consecutive bcids.
- Are usually associated to a pedestal shift double pedestal distributions

• Identified by checking the previous bcid, if small difference \rightarrow tagged.

Plane event: similar cause ? Identified easily by selecting events with less than X channels triggered (X depends on the beam composition, usually 32 is a right number)

Underflow data (ADC=4):

- a) by sampling in the undershot (in principle solved/reduced in sk2a)
- b) only at SCA, due to some noise (and timing) extra sensitivity on analog part intrinsic to skiroc2 (in principle solved in 2a) → very located channels, probably near some power/other lines that introduce some noise in the analog part of the chip.

Tagging these events: badbcid

- How are all these events identified ?
- Using the nhits[16][15] variable (counts all hits in one SCA with ADC>10)
- Using the badbcid[16][15] variable. It is filled doing the following checks sequentially:
 - ==0 if SCA=0
 - ==1-16 if bcid[chip][sca]-bcid[chip][sca-1]=1-16
 - = = +32 if a negative entry (ADC<10) is found in the chip for this sca
 - ==0 if none of the previous.

Tagging these events: badbcid

Issues observed:

- We tag the bcid+1 events as bad events
- SCA 0 is always tagged as good but we see some double pedestals (see Yu's slides)

Solution ?

- ==1-16 if bcid[chip][sca+1]-bcid[chip][sca]=1-16
- = = +32 if a negative entry (ADC<10) is found in the chip for this sca
- ==0 if none of the previous.
- New RAW2ROOT version to be updated (and checked) in the repository

